

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

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 APPLICANT
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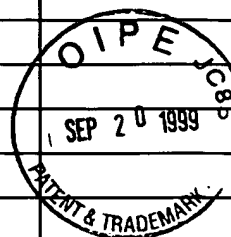
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U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE



FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	

 RECEIVED
SEP 22 1999
TECH CENTER 2700
Translation Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

VB	Paul B. Chou et al., "Automatic Defect Classification for Semiconductor Manufacturing", <i>Machine Vision and Applications</i> , 1997, pp. 201-213.
VB	Rivi Sherman et al., "An Automatic Defect Classification System for Semiconductor Wafers", <i>Machine Vision Applications in Industrial Inspection</i> , SPIE Vol. 1907, 1993, pp. 72-78.
VB	Louis Breau et al., "Automatic Defect Classification System for Patterned Semiconductor Wafers", 1995 International Symposium on Semiconductor Manufacturing., pp. 69-73.1
EXAMINER	DATE CONSIDERED 5/12/02